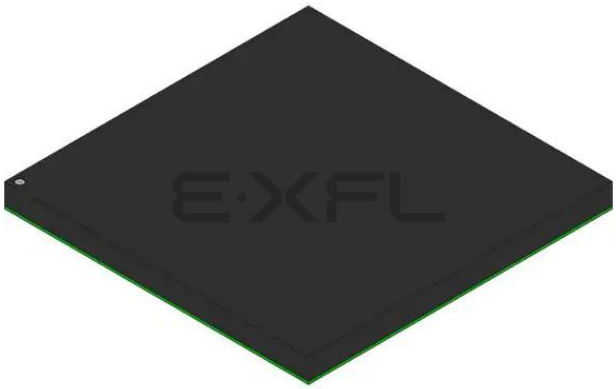

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Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	-
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1508-BBGA, FCBGA
Supplier Device Package	1508-FBGA (30x30)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep2s180f1508i4

About this Handbook

This handbook provides comprehensive information about the Altera® Stratix® II family of devices.

How to Contact Altera

For the most up-to-date information about Altera products, refer to the following table.

Contact *(1)*	Contact Method	Address
Technical support	Website	www.altera.com/support
Technical training	Website	www.altera.com/training
	Email	custrain@altera.com
Product literature	Email	www.altera.com/literature
Altera literature services	Website	literature@altera.com
Non-technical support (General)	Email	nacomp@altera.com
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Note to table:
(1) You can also contact your local Altera sales office or sales representative.

Typographic Conventions

This document uses the typographic conventions shown below.

Visual Cue	Meaning
Bold Type with Initial Capital Letters	Command names, dialog box titles, checkbox options, and dialog box options are shown in bold, initial capital letters. Example: **Save As** dialog box.
bold type	External timing parameters, directory names, project names, disk drive names, filenames, filename extensions, and software utility names are shown in bold type. Examples: $\mathbf{f_{MAX}}$, **\qdesigns** directory, **d:** drive, **chiptrip.gdf** file.
Italic Type with Initial Capital Letters	Document titles are shown in italic type with initial capital letters. Example: *AN 75: High-Speed Board Design.*

Stratix II devices are available in up to three speed grades, -3, -4, and -5, with -3 being the fastest. Table 1–5 shows Stratix II device speed-grade offerings.

Table 1–5. Stratix II Device Speed Grades

Device	Temperature Grade	484-Pin FineLine BGA	484-Pin Hybrid FineLine BGA	672-Pin FineLine BGA	780-Pin FineLine BGA	1,020-Pin FineLine BGA	1,508-Pin FineLine BGA
EP2S15	Commercial	-3, -4, -5		-3, -4, -5			
	Industrial	-4		-4			
EP2S30	Commercial	-3, -4, -5		-3, -4, -5			
	Industrial	-4		-4			
EP2S60	Commercial	-3, -4, -5		-3, -4, -5		-3, -4, -5	
	Industrial	-4		-4		-4	
EP2S90	Commercial		-4, -5		-4, -5	-3, -4, -5	-3, -4, -5
	Industrial					-4	-4
EP2S130	Commercial				-4, -5	-3, -4, -5	-3, -4, -5
	Industrial					-4	-4
EP2S180	Commercial					-3, -4, -5	-3, -4, -5
	Industrial					-4	-4

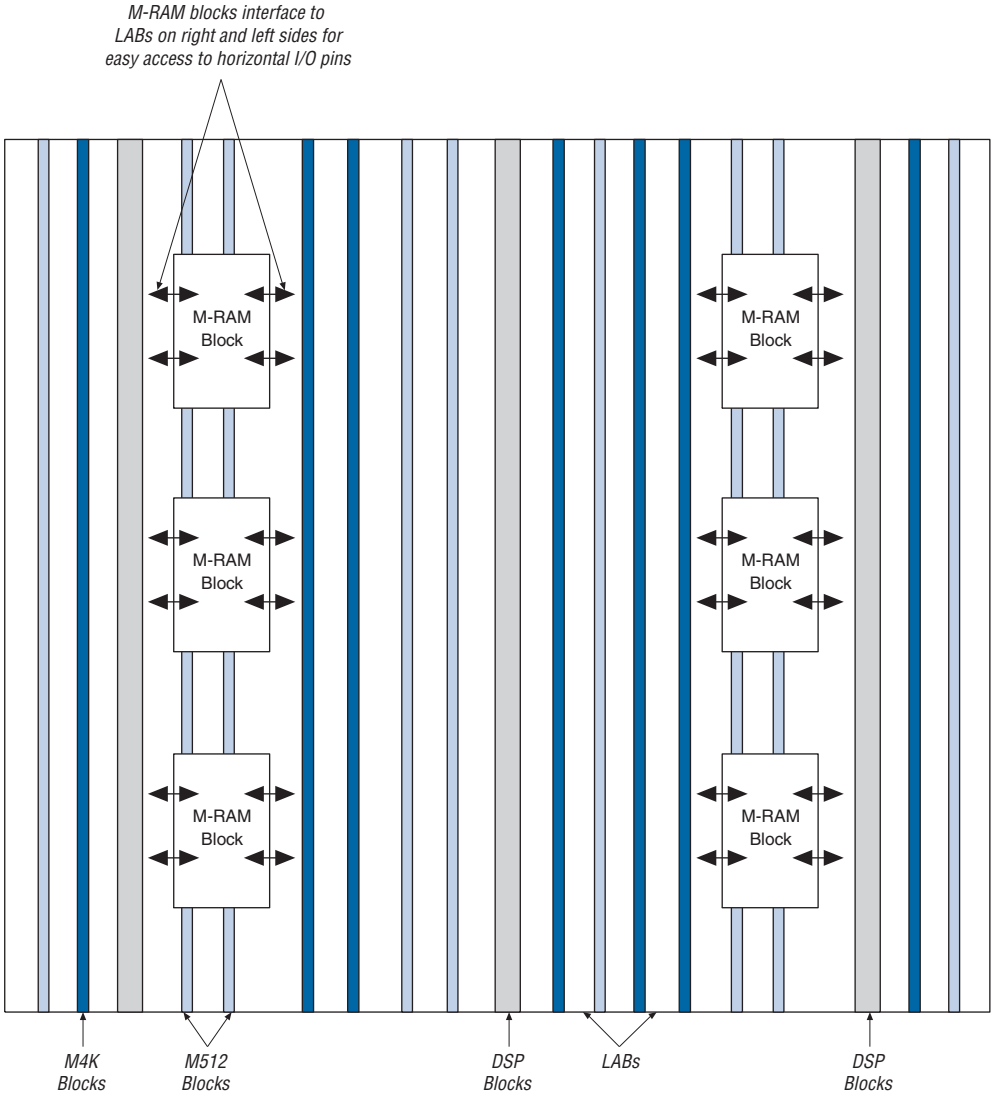
R24 row interconnects span 24 LABs and provide the fastest resource for long row connections between LABs, TriMatrix memory, DSP blocks, and Row IOEs. The R24 row interconnects can cross M-RAM blocks. R24 row interconnects drive to other row or column interconnects at every fourth LAB and do not drive directly to LAB local interconnects. R24 row interconnects drive LAB local interconnects via R4 and C4 interconnects. R24 interconnects can drive R24, R4, C16, and C4 interconnects.

The column interconnect operates similarly to the row interconnect and vertically routes signals to and from LABs, TriMatrix memory, DSP blocks, and IOEs. Each column of LABs is served by a dedicated column interconnect. These column resources include:

- Shared arithmetic chain interconnects in an LAB
- Carry chain interconnects in an LAB and from LAB to LAB
- Register chain interconnects in an LAB
- C4 interconnects traversing a distance of four blocks in up and down direction
- C16 column interconnects for high-speed vertical routing through the device

Stratix II devices include an enhanced interconnect structure in LABs for routing shared arithmetic chains and carry chains for efficient arithmetic functions. The register chain connection allows the register output of one ALM to connect directly to the register input of the next ALM in the LAB for fast shift registers. These ALM to ALM connections bypass the local interconnect. The Quartus II Compiler automatically takes advantage of these resources to improve utilization and performance. Figure 2–17 shows the shared arithmetic chain, carry chain and register chain interconnects.

Figure 2–24. EP2S130 Device with M-RAM Interface Locations *Note (1)*



Note to Figure 2–24:

(1) The device shown is an EP2S130 device. The number and position of M-RAM blocks varies in other devices.

The DSP block is divided into four block units that interface with four LAB rows on the left and right. Each block unit can be considered one complete 18 × 18-bit multiplier with 36 inputs and 36 outputs. A local interconnect region is associated with each DSP block. Like an LAB, this interconnect region can be fed with 16 direct link interconnects from the LAB to the left or right of the DSP block in the same row. R4 and C4 routing resources can access the DSP block's local interconnect region. The outputs also work similarly to LAB outputs as well. Eighteen outputs from the DSP block can drive to the left LAB through direct link interconnects and eighteen can drive to the right LAB though direct link interconnects. All 36 outputs can drive to R4 and C4 routing interconnects. Outputs can drive right- or left-column routing. Figures 2–29 and 2–30 show the DSP block interfaces to LAB rows.

Figure 2–29. DSP Block Interconnect Interface

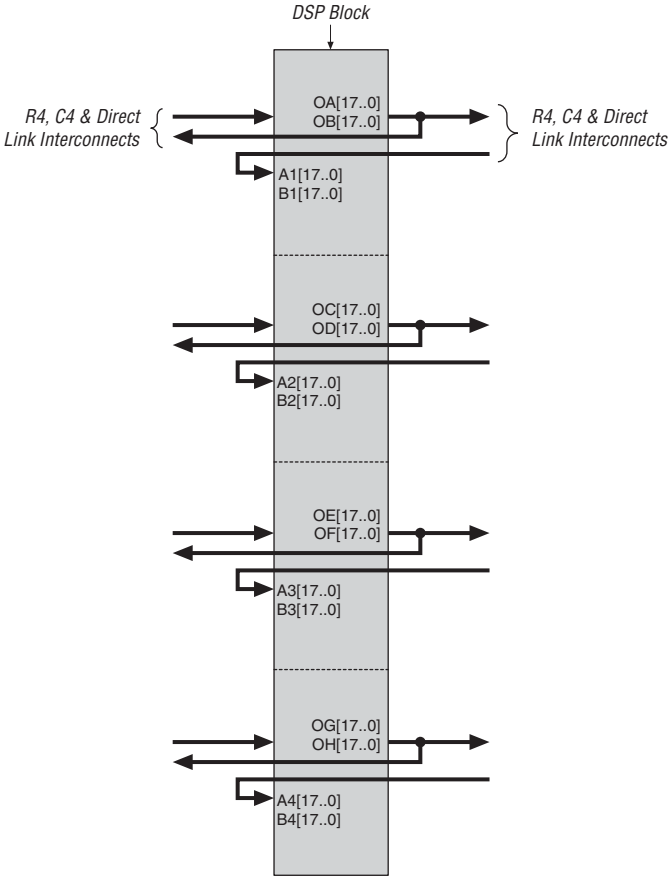
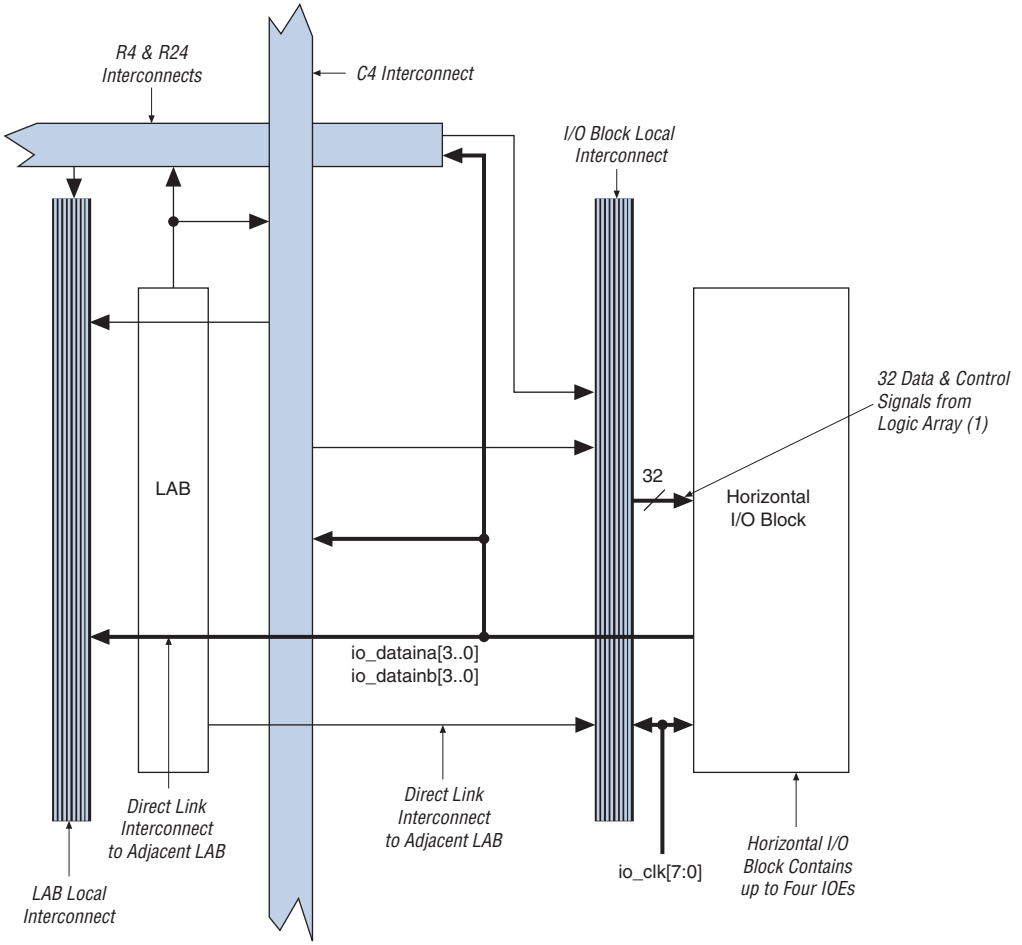


Table 2–12. Global & Regional Clock Connections from Bottom Clock Pins & Enhanced PLL Outputs (Part 2 of 2)

Bottom Side Global & Regional Clock Network Connectivity	DLLCLK	CLK4	CLK5	CLK6	CLK7	RCLK8	RCLK9	RCLK10	RCLK11	RCLK12	RCLK13	RCLK14	RCLK15
GCLKDRV3					✓								
RCLKDRV0						✓				✓			
RCLKDRV1							✓				✓		
RCLKDRV2								✓				✓	
RCLKDRV3									✓				✓
RCLKDRV4						✓				✓			
RCLKDRV5							✓				✓		
RCLKDRV6								✓				✓	
RCLKDRV7									✓				✓
Enhanced PLL 6 outputs													
c0	✓	✓	✓			✓				✓			
c1	✓	✓	✓				✓				✓		
c2	✓			✓	✓			✓				✓	
c3	✓			✓	✓				✓				✓
c4	✓					✓		✓		✓		✓	
c5	✓						✓		✓		✓		✓
Enhanced PLL 12 outputs													
c0		✓	✓			✓				✓			
c1		✓	✓				✓				✓		
c2				✓	✓			✓				✓	
c3				✓	✓				✓				✓
c4						✓		✓		✓		✓	
c5							✓		✓		✓		✓

Figure 2–47. Row I/O Block Connection to the Interconnect *Note (1)*



Note to Figure 2–47:

(1) The 32 data and control signals consist of eight data out lines: four lines each for DDR applications `io_dataouta[3..0]` and `io_dataoutb[3..0]`, four output enables `io_oe[3..0]`, four input clock enables `io_ce_in[3..0]`, four output clock enables `io_ce_out[3..0]`, four clocks `io_clk[3..0]`, four asynchronous clear and preset signals `io_aclr/apreset[3..0]`, and four synchronous clear and preset signals `io_sclr/spreset[3..0]`.

Table 2–19. Board Design Recommendations for nCEO

nCE Input Buffer Power in I/O Bank 3	Stratix II nCEO V_{CCIO} Voltage Level in I/O Bank 7				
	V_{CCIO} = 3.3 V	V_{CCIO} = 2.5 V	V_{CCIO} = 1.8 V	V_{CCIO} = 1.5 V	V_{CCIO} = 1.2 V
VCCSEL high (V_{CCIO} Bank 3 = 1.5 V)	✓ *(1), (2)*	✓ *(3), (4)*	✓ *(5)*	✓	✓
VCCSEL high (V_{CCIO} Bank 3 = 1.8 V)	✓ *(1), (2)*	✓ *(3), (4)*	✓	✓	Level shifter required
VCCSEL low (nCE Powered by V_{CCPD} = 3.3V)	✓	✓ *(4)*	✓ *(6)*	Level shifter required	Level shifter required

Notes to Table 2–19:

(1) Input buffer is 3.3-V tolerant.
(2) The nCEO output buffer meets V_{OH} (MIN) = 2.4 V.
(3) Input buffer is 2.5-V tolerant.
(4) The nCEO output buffer meets V_{OH} (MIN) = 2.0 V.
(5) Input buffer is 1.8-V tolerant.
(6) An external 250-Ω pull-up resistor is not required, but recommended if signal levels on the board are not optimal.

For JTAG chains, the TDO pin of the first device drives the TDI pin of the second device in the chain. The V_{CCSEL} input on JTAG input I/O cells (TCK, TMS, TDI, and TRST) is internally hardwired to GND selecting the 3.3-V/2.5-V input buffer powered by V_{CCPD}. The ideal case is to have the V_{CCIO} of the TDO bank from the first device to match the V_{CCSEL} settings for TDI on the second device, but that may not be possible depending on the application. Table 2–20 contains board design recommendations to ensure proper JTAG chain operation.

Table 2–20. Supported TDO/TDI Voltage Combinations (Part 1 of 2)

Device	TDI Input Buffer Power	Stratix II TDO V_{CCIO} Voltage Level in I/O Bank 4				
		V_{CCIO} = 3.3 V	V_{CCIO} = 2.5 V	V_{CCIO} = 1.8 V	V_{CCIO} = 1.5 V	V_{CCIO} = 1.2 V
Stratix II	Always V_{CCPD} (3.3V)	✓ *(1)*	✓ *(2)*	✓ *(3)*	Level shifter required	Level shifter required

the Device & Pin Options dialog box in the Quartus II software uses a 32-bit CRC circuit to ensure data reliability and is one of the best options for mitigating SEU.

You can implement the error detection CRC feature with existing circuitry in Stratix II devices, eliminating the need for external logic. For Stratix II devices, CRC is computed by the device during configuration and checked against an automatically computed CRC during normal operation. The CRC_ERROR pin reports a soft error when configuration SRAM data is corrupted, triggering device reconfiguration.

Custom-Built Circuitry

Dedicated circuitry is built in the Stratix II devices to perform error detection automatically. This error detection circuitry in Stratix II devices constantly checks for errors in the configuration SRAM cells while the device is in user mode. You can monitor one external pin for the error and use it to trigger a re-configuration cycle. You can select the desired time between checks by adjusting a built-in clock divider.

Software Interface

In the Quartus II software version 4.1 and later, you can turn on the automated error detection CRC feature in the Device & Pin Options dialog box. This dialog box allows you to enable the feature and set the internal frequency of the CRC between 400 kHz to 50 MHz. This controls the rate that the CRC circuitry verifies the internal configuration SRAM bits in the FPGA device.

For more information on CRC, refer to *AN 357: Error Detection Using CRC in Altera FPGA Devices*.

Document Revision History

Table 3–7 shows the revision history for this chapter.

Table 3–7. Document Revision History (Part 1 of 2)

Date and Document Version	Changes Made	Summary of Changes
May 2007, v4.2	Moved Document Revision History section to the end of the chapter.	—
	Updated the "Temperature Sensing Diode (TSD)" section.	—

Table 5–4. Stratix II Device DC Operating Conditions (Part 2 of 2) *Note (1)*

Symbol	Parameter	Conditions		Minimum	Typical	Maximum	Unit
I_{CCI00}	V_{CCIO} supply current (standby)	V_I = ground, no load, no toggling inputs T_J = 25° C	EP2S15		4.0	*(3)*	mA
			EP2S30		4.0	*(3)*	mA
			EP2S60		4.0	*(3)*	mA
			EP2S90		4.0	*(3)*	mA
			EP2S130		4.0	*(3)*	mA
			EP2S180		4.0	*(3)*	mA
R_{CONF} *(4)*	Value of I/O pin pull-up resistor before and during configuration	Vi = 0; V_{CCIO} = 3.3 V		10	25	50	kΩ
		Vi = 0; V_{CCIO} = 2.5 V		15	35	70	kΩ
		Vi = 0; V_{CCIO} = 1.8 V		30	50	100	kΩ
		Vi = 0; V_{CCIO} = 1.5 V		40	75	150	kΩ
		Vi = 0; V_{CCIO} = 1.2 V		50	90	170	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration				1	2	kΩ

Notes to Table 5–4:

(1) Typical values are for T_A = 25°C, V_{CCINT} = 1.2 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(2) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(3) Maximum values depend on the actual T_J and design utilization. See the Excel-based PowerPlay Early Power Estimator (available at **www.altera.com**) or the Quartus II PowerPlay Power Analyzer feature for maximum values. See the section "Power Consumption" on page 5–20 for more information.

(4) Pin pull-up resistance values are lower if an external source drives the pin higher than V_{CCIO}.

I/O Standard Specifications

Tables 5–5 through 5–32 show the Stratix II device family I/O standard specifications.

Table 5–5. LVTTL Specifications (Part 1 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} *(1)*	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	I_{OH} = –4 mA *(2)*	2.4		V

Table 5–5. LVTTL Specifications (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{OL}	Low-level output voltage	I_{OL} = 4 mA *(2)*		0.45	V

Notes to Tables 5–5:

(1) Stratix II devices comply to the narrow range for the supply voltage as specified in the EIA/JEDEC Standard, JESD8-B.

(2) This specification is supported across all the programmable drive strength settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–6. LVCMOS Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} *(1)*	Output supply voltage		3.135	3.465	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.8	V
V_{OH}	High-level output voltage	V_{CCIO} = 3.0, I_{OH} = –0.1 mA *(2)*	V_{CCIO} – 0.2		V
V_{OL}	Low-level output voltage	V_{CCIO} = 3.0, I_{OL} = 0.1 mA *(2)*		0.2	V

Notes to Table 5–6:

(1) Stratix II devices comply to the narrow range for the supply voltage as specified in the EIA/JEDEC Standard, JESD8-B.

(2) This specification is supported across all the programmable drive strength available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–7. 2.5-V I/O Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO} *(1)*	Output supply voltage		2.375	2.625	V
V_{IH}	High-level input voltage		1.7	4.0	V
V_{IL}	Low-level input voltage		–0.3	0.7	V
V_{OH}	High-level output voltage	I_{OH} = –1mA *(2)*	2.0		V
V_{OL}	Low-level output voltage	I_{OL} = 1 mA *(2)*		0.4	V

Notes to Table 5–7:

(1) Stratix II devices V_{CCIO} voltage level support of 2.5 ± -5% is narrower than defined in the Normal Range of the EIA/JEDEC standard.

(2) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Figure 5–1. Receiver Input Waveforms for Differential I/O Standards

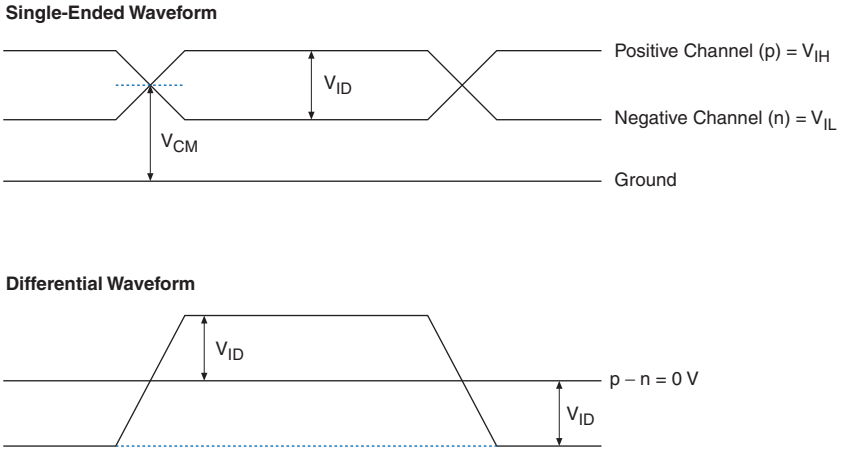


Figure 5–2. Transmitter Output Waveforms for Differential I/O Standards

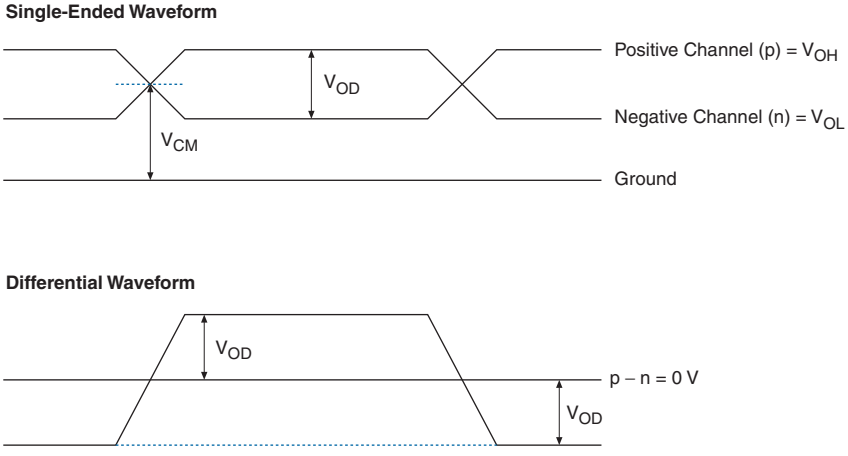


Table 5–23. 1.5-V HSTL Class I Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.425	1.500	1.575	V
V_{REF}	Input reference voltage		0.713	0.750	0.788	V
V_{TT}	Termination voltage		0.713	0.750	0.788	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 8 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –8 mA *(1)*			0.4	V

Note to Table 5–23:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Table 5–24. 1.5-V HSTL Class II Specifications

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V_{CCIO}	Output supply voltage		1.425	1.500	1.575	V
V_{REF}	Input reference voltage		0.713	0.750	0.788	V
V_{TT}	Termination voltage		0.713	0.750	0.788	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = 16 mA *(1)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OH} = –16 mA *(1)*			0.4	V

Note to Table 5–24:

(1) This specification is supported across all the programmable drive settings available for this I/O standard as shown in the *Stratix II Architecture* chapter in volume 1 of the *Stratix II Device Handbook*.

Bus Hold Specifications

Table 5–29 shows the Stratix II device family bus hold specifications.

Table 5–29. Bus Hold Parameters

Parameter	Conditions	V_{CCIO} Level										Unit
		1.2 V		1.5 V		1.8 V		2.5 V		3.3 V		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Low sustaining current	$V_{IN} > V_{IL}$ (maximum)	22.5		25.0		30.0		50.0		70.0		µA
High sustaining current	$V_{IN} < V_{IH}$ (minimum)	–22.5		–25.0		–30.0		–50.0		–70.0		µA
Low overdrive current	0 V < V_{IN} < V_{CCIO}		120		160		200		300		500	µA
High overdrive current	0 V < V_{IN} < V_{CCIO}		–120		–160		–200		–300		–500	µA
Bus-hold trip point		0.45	0.95	0.50	1.00	0.68	1.07	0.70	1.70	0.80	2.00	V

On-Chip Termination Specifications

Tables 5–30 and 5–31 define the specification for internal termination resistance tolerance when using series or differential on-chip termination.

Table 5–30. Series On-Chip Termination Specification for Top & Bottom I/O Banks (Part 1 of 2)
Notes (1), 2

Symbol	Description	Conditions	Resistance Tolerance		Unit
			Commercial Max	Industrial Max	
25-Ω R_S 3.3/2.5	Internal series termination with calibration (25-Ω setting)	V_{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 3.3/2.5 V	±30	±30	%

Table 5–30. Series On-Chip Termination Specification for Top & Bottom I/O Banks (Part 2 of 2)
Notes (1), 2

Symbol	Description	Conditions	Resistance Tolerance		
			Commercial Max	Industrial Max	Unit
50-Ω R_S 3.3/2.5	Internal series termination with calibration (50-Ω setting)	V_{CCIO} = 3.3/2.5 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 3.3/2.5 V	±30	±30	%
50-Ω R_T 2.5	Internal parallel termination with calibration (50-Ω setting)	V_{CCIO} = 1.8 V	±30	±30	%
25-Ω R_S 1.8	Internal series termination with calibration (25-Ω setting)	V_{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8 V	±30	±30	%
50-Ω R_S 1.8	Internal series termination with calibration (50-Ω setting)	V_{CCIO} = 1.8 V	±5	±10	%
	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 V	±30	±30	%
50-Ω R_T 1.8	Internal parallel termination with calibration (50-Ω setting)	V_{CCIO} = 1.8 V	±10	±15	%
50–Ω R_S 1.5	Internal series termination with calibration (50-Ω setting)	V_{CCIO} = 1.5 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.5 V	±36	±36	%
50-Ω R_T 1.5	Internal parallel termination with calibration (50-Ω setting)	V_{CCIO} = 1.5 V	±10	±15	%
50–Ω R_S 1.2	Internal series termination with calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±8	±10	%
	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
50-Ω R_T 1.2	Internal parallel termination with calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±10	±15	%

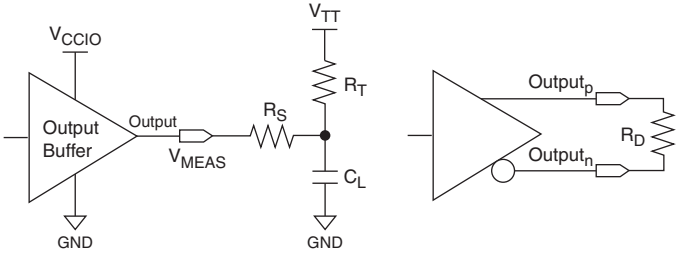
Notes for Table 5–30:
(1) The resistance tolerances for calibrated SOCT and POCT are for the moment of calibration. If the temperature or voltage changes over time, the tolerance may also change.
(2) On-chip parallel termination with calibration is only supported for input pins.

4. Record the time to V_{MEAS}.

5. Compare the results of steps 2 and 4. The increase or decrease in delay should be added to or subtracted from the I/O Standard Output Adder delays to yield the actual worst-case propagation delay (clock-to-output) of the PCB trace.

The Quartus II software reports the timing with the conditions shown in Table 5–34 using the above equation. Figure 5–4 shows the model of the circuit that is represented by the output timing of the Quartus II software.

Figure 5–4. Output Delay Timing Reporting Setup Modeled by Quartus II



Notes to Figure 5–4:

(1) Output pin timing is reported at the output pin of the FPGA device. Additional delays for loading and board trace delay need to be accounted for with IBIS model simulations.

(2) V_{CCPD} is 3.085 V unless otherwise specified.

(3) V_{CCINT} is 1.12 V unless otherwise specified.

Figures 5–5 and 5–6 show the measurement setup for output disable and output enable timing.

Table 5–36. Stratix II Performance Notes (Part 6 of 6) Note (1)

Applications		Resources Used			Performance				
		ALUTs	TriMatrix Memory Blocks	DSP Blocks	-3 Speed Grade (2)	-3 Speed Grade (3)	-4 Speed Grade	-5 Speed Grade	Unit
Larger designs	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, three multipliers five adders FFT function	7385	60	36	359.58	352.98	312.01	278.00	MHz
	8-bit, 1024-point, quadrant output, four parallel FFT engines, buffered burst, four multipliers and two adders FFT function	6601	60	48	371.88	355.74	327.86	277.62	MHz

Notes for Table 5–36:

(1) These design performance numbers were obtained using the Quartus II software version 5.0 SP1.
(2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
(3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
(4) This application uses registered inputs and outputs.
(5) This application uses registered multiplier input and output stages within the DSP block.
(6) This application uses registered multiplier input, pipeline, and output stages within the DSP block.
(7) This application uses registered multiplier input with output of the multiplier stage feeding the accumulator or subtractor within the DSP block.
(8) This application uses the same clock source that is globally routed and connected to ports A and B.
(9) This application uses locally routed clocks or differently sourced clocks for ports A and B.

Table 5–40. M512 Block Internal Timing Microparameters (Part 2 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
$t_{M512DATACO1}$	Clock-to-output delay when using output registers	298	478	298	501	284 298	548	298	640	ps
$t_{M512DATACO2}$	Clock-to-output delay without output registers	2,102	2,345	2,102	2,461	2,003 2,102	2,695	2,102	3,141	ps
$t_{M512CLKL}$	Minimum clock low time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLKH}$	Minimum clock high time	1,315		1,380		1,512 1,512		1,762		ps
$t_{M512CLR}$	Minimum clear pulse width	144		151		165 165		192		ps

Notes to Table 5–40:

(1) F_{MAX} of M512 block obtained using the Quartus II software does not necessarily equal to 1/TM512RC.
(2) These numbers apply to -3 speed grade EP2S15, EP2S30, EP2S60, and EP2S90 devices.
(3) These numbers apply to -3 speed grade EP2S130 and EP2S180 devices.
(4) For the -3 and -5 speed grades, the minimum timing is for the commercial temperature grade. Only -4 speed grade devices offer the industrial temperature grade.
(5) For the -4 speed grade, the first number is the minimum timing parameter for industrial devices. The second number is the minimum timing parameter for commercial devices.

Table 5–41. M4K Block Internal Timing Microparameters (Part 1 of 2) *Note (1)*

Symbol	Parameter	-3 Speed Grade (2)		-3 Speed Grade (3)		-4 Speed Grade		-5 Speed Grade		Unit
		Min (4)	Max	Min (4)	Max	Min (5)	Max	Min (4)	Max	
t_{M4KRC}	Synchronous read cycle time	1,462	2,240	1,462	2,351	1,393 1,462	2,575	1,462	3,000	ps
$t_{M4KWERESU}$	Write or read enable setup time before clock	22		23		25 25		29		ps
$t_{M4KWEREH}$	Write or read enable hold time after clock	203		213		233 233		272		ps
$t_{M4KBESU}$	Byte enable setup time before clock	22		23		25 25		29		ps
t_{M4KBEH}	Byte enable hold time after clock	203		213		233 233		272		ps

Table 5–71. Default Loading of Different I/O Standards for Stratix II (Part 2 of 2)

I/O Standard	Capacitive Load	Unit
SSTL-2 Class II	0	pF
SSTL-18 Class I	0	pF
SSTL-18 Class II	0	pF
1.5-V HSTL Class I	0	pF
1.5-V HSTL Class II	0	pF
1.8-V HSTL Class I	0	pF
1.8-V HSTL Class II	0	pF
1.2-V HSTL with OCT	0	pF
Differential SSTL-2 Class I	0	pF
Differential SSTL-2 Class II	0	pF
Differential SSTL-18 Class I	0	pF
Differential SSTL-18 Class II	0	pF
1.5-V Differential HSTL Class I	0	pF
1.5-V Differential HSTL Class II	0	pF
1.8-V Differential HSTL Class I	0	pF
1.8-V Differential HSTL Class II	0	pF
LVDS	0	pF
HyperTransport	0	pF
LVPECL	0	pF